Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/701,258	LANG ET AL.	
Examiner	Art Unit	
Jeffrey D. Lane	2828	

Subclass	CHED Date	Examiner
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
diffraction efficiency	4/6/2006	JL		